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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	20MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	LVD, POR, PWM, WDT
Number of I/O	39
Program Memory Size	48KB (48K x 8)
Program Memory Type	FLASH
EEPROM Size	256 x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/s9s08rna48w1mlf

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1 Ordering parts

1.1 Determining valid orderable parts

Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to www.freescale.com and perform a part number search for the following device numbers: RN60, RN48 and RN32.

2 Part identification

2.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

2.2 Format

Part numbers for this device have the following format:

S 9 S08 RN AA F1 B CC

2.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
S	Qualification status	• S = fully qualified, general market flow
9	Memory	• 9 = flash based
S08	Core	• S08 = 8-bit CPU
RN	Device family	• RN
AA	Approximate flash size in KB	• 60 = 60 KB • 48 = 48 KB • 32 = 32 KB
F1	Fab and mask set identifier	• W1
B	Temperature range (°C)	• M = -40 to 125

Table continues on the next page...

Field	Description	Values
CC	Package designator	- LH = 64-pin LQFP - LF = 48-pin LQFP - LC = 32-pin LQFP

2.4 Example

This is an example part number:

S9S08RN60W1MLH

3 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding, the following classification is used and the parameters are tagged accordingly in the tables where appropriate:

Table 1. Parameter Classifications

P	Those parameters are guaranteed during production testing on each individual device.
C	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
T	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

NOTE

The classification is shown in the column labeled “C” in the parameter tables where appropriate.

4 Ratings

4.1 Thermal handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
T _{STG}	Storage temperature	–55	150	°C	1
T _{SDR}	Solder temperature, lead-free	—	260	°C	2

1. Determined according to JEDEC Standard JESD22-A103, *High Temperature Storage Life*.

Symbol	Description	Min.	Max.	Unit
V_{DIO}	Digital input voltage (except RESET, EXTAL, XTAL, or true open drain pin PTA2 and PTA3)	-0.3	$V_{DD} + 0.3$	V
	Digital input voltage (true open drain pin PTA2 and PTA3)	-0.3	6	V
V_{AIO}	Analog ¹ , RESET, EXTAL, and XTAL input voltage	-0.3	$V_{DD} + 0.3$	V
I_D	Instantaneous maximum current single pin limit (applies to all port pins)	-25	25	mA
V_{DDA}	Analog supply voltage	$V_{DD} - 0.3$	$V_{DD} + 0.3$	V

1. All digital I/O pins, except open-drain pin PTA2 and PTA3, are internally clamped to V_{SS} and V_{DD} . PTA2 and PTA3 is only clamped to V_{SS} .

5 General

5.1 Nonswitching electrical specifications

5.1.1 DC characteristics

This section includes information about power supply requirements and I/O pin characteristics.

Table 2. DC characteristics

Symbol	C	Descriptions			Min	Typical ¹	Max	Unit
—	—	Operating voltage			2.7	—	5.5	V
V_{OH}	C	Output high voltage	All I/O pins, standard-drive strength	5 V, $I_{load} = -5$ mA	$V_{DD} - 0.8$	—	—	V
	C			3 V, $I_{load} = -2.5$ mA	$V_{DD} - 0.8$	—	—	V
	C	High current drive pins, high-drive strength ^{2, 2}		5 V, $I_{load} = -20$ mA	$V_{DD} - 0.8$	—	—	V
	C			3 V, $I_{load} = -10$ mA	$V_{DD} - 0.8$	—	—	V
I_{OHT}	D	Output high current	Max total I_{OH} for all ports	5 V	—	—	-100	mA
				3 V	—	—	-50	
V_{OL}	C	Output low voltage	All I/O pins, standard-drive strength	5 V, $I_{load} = 5$ mA	—	—	0.8	V
	C			3 V, $I_{load} = 2.5$ mA	—	—	0.8	V
	C	High current drive pins, high-drive strength ²		5 V, $I_{load} = 20$ mA	—	—	0.8	V
	C			3 V, $I_{load} = 10$ mA	—	—	0.8	V

Table continues on the next page...

Table 2. DC characteristics (continued)

Symbol	C	Descriptions			Min	Typical ¹	Max	Unit
I_{OLT}	D	Output low current	Max total I_{OL} for all ports	5 V	—	—	100	mA
				3 V	—	—	50	
V_{IH}	P	Input high voltage	All digital inputs	$V_{DD} > 4.5V$	$0.70 \times V_{DD}$	—	—	V
	C			$V_{DD} > 2.7V$	$0.75 \times V_{DD}$	—	—	
V_{IL}	P	Input low voltage	All digital inputs	$V_{DD} > 4.5V$	—	—	$0.30 \times V_{DD}$	V
	C			$V_{DD} > 2.7V$	—	—	$0.35 \times V_{DD}$	
V_{hys}	C	Input hysteresis	All digital inputs	—	$0.06 \times V_{DD}$	—	—	mV
I_{In}	P	Input leakage current	All input only pins (per pin)	$V_{IN} = V_{DD}$ or V_{SS}	—	0.1	1	μA
I_{OZ}	P	Hi-Z (off-state) leakage current	All input/output (per pin)	$V_{IN} = V_{DD}$ or V_{SS}	—	0.1	1	μA
I_{OZTOT}	C	Total leakage combined for all inputs and Hi-Z pins	All input only and I/O	$V_{IN} = V_{DD}$ or V_{SS}	—	—	2	μA
R_{PU}	P	Pullup resistors	All digital inputs, when enabled (all I/O pins other than PTA2 and PTA3)	—	30.0	—	50.0	k Ω
R_{PU}^3	P	Pullup resistors	PTA2 and PTA3 pin	—	30.0	—	60.0	k Ω
I_{IC}	D	DC injection current ^{4, 5, 6}	Single pin limit	$V_{IN} < V_{SS}$, $V_{IN} > V_{DD}$	-0.2	—	2	mA
			Total MCU limit, includes sum of all stressed pins		-5	—	25	
C_{in}	C	Input capacitance, all pins		—	—	—	7	pF
V_{RAM}	C	RAM retention voltage		—	2.0	—	—	V

1. Typical values are measured at 25 °C. Characterized, not tested.
2. Only PTB4, PTB5 support ultra high current output.
3. The specified resistor value is the actual value internal to the device. The pullup value may appear higher when measured externally on the pin.
4. All functional non-supply pins, except for PTA2 and PTA3, are internally clamped to V_{SS} and V_{DD} .
5. Input must be current-limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the large one.
6. Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If the positive injection current ($V_{IN} > V_{DD}$) is higher than I_{DD} , the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Ensure that external V_{DD} load will shunt current higher than maximum injection current when the MCU is not consuming power, such as no system clock is present, or clock rate is very low (which would reduce overall power consumption).

Table 3. LVD and POR Specification

Symbol	C	Description	Min	Typ	Max	Unit
V_{POR}	D	POR re-arm voltage ^{1, 2}	1.5	1.75	2.0	V

Table continues on the next page...

Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (low drive strength) ($V_{DD} = 5\text{ V}$)

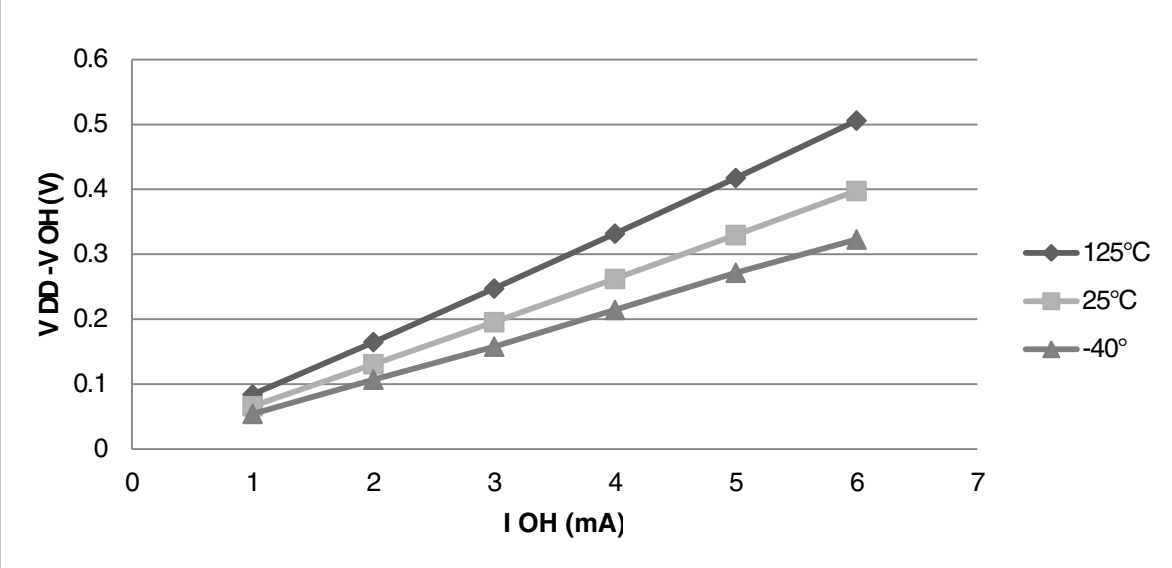


Figure 1. Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (standard drive strength) ($V_{DD} = 5\text{ V}$)

Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (low drive strength) ($V_{DD} = 3\text{ V}$)

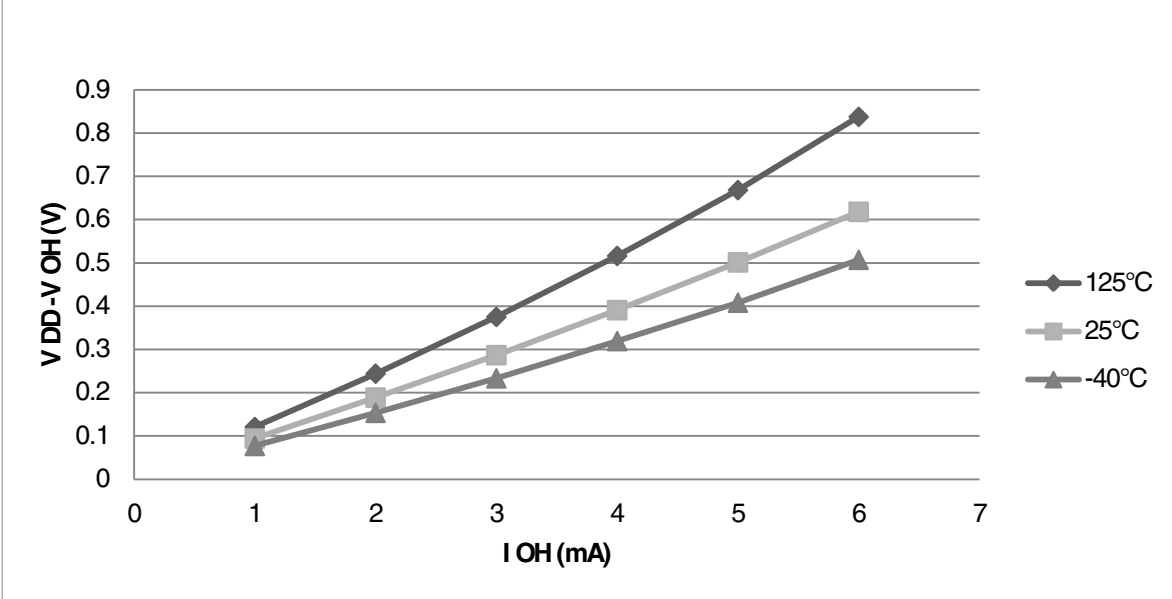


Figure 2. Typical I_{OH} Vs. $V_{DD}-V_{OH}$ (standard drive strength) ($V_{DD} = 3\text{ V}$)

Typical I_{OL} Vs. V_{OL} (low drive strength) ($V_{DD} = 5\text{ V}$)

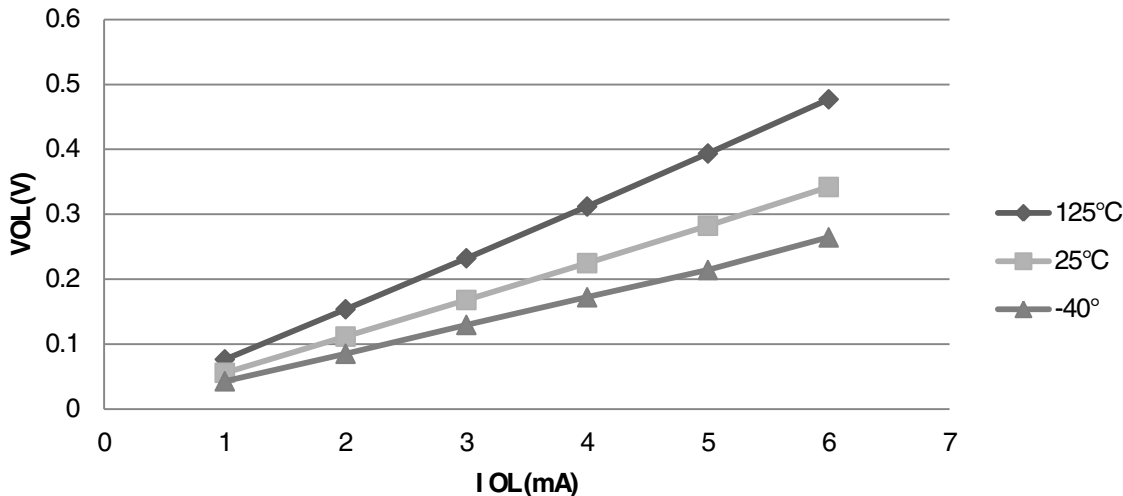


Figure 5. Typical I_{OL} Vs. V_{OL} (standard drive strength) ($V_{DD} = 5\text{ V}$)

Typical I_{OL} Vs. V_{OL} (low drive strength) ($V_{DD} = 3\text{ V}$)

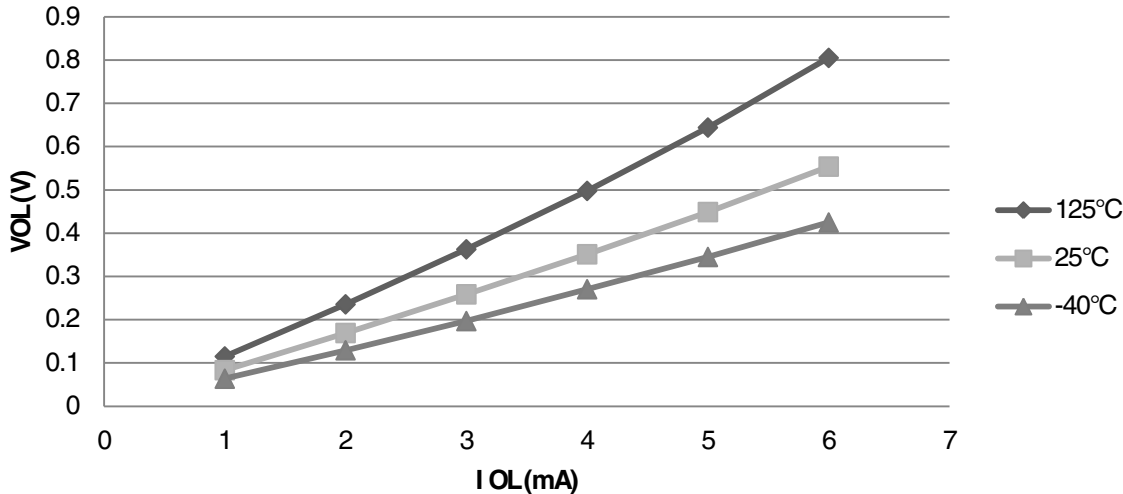


Figure 6. Typical I_{OL} Vs. V_{OL} (standard drive strength) ($V_{DD} = 3\text{ V}$)

Table 4. Supply current characteristics (continued)

Num	C	Parameter	Symbol	Bus Freq	V _{DD} (V)	Typical ¹	Max	Unit	Temp
7	C	ADC adder to stop3	—	—	5	44	—	μA	-40 to 125 °C
	C	ADLPC = 1 ADLSMP = 1 ADCO = 1 MODE = 10B ADICLK = 11B	—	—	3	40	—		
8	C	TSI adder to stop3 ⁴	—	—	5	111	—	μA	-40 to 125 °C
	C	PS = 010B NSCN = 0x0F EXTCHRG = 0 REFCHRG = 0 DVOLT = 01B	—	—	3	110	—		
9	C	LVD adder to stop3 ⁵	—	—	5	130	—	μA	-40 to 125 °C
	C		—	—	3	125	—		

1. Data in Typical column was characterized at 5.0 V, 25 °C or is typical recommended value.
2. RTC adder cause <1 μA I_{DD} increase typically, RTC clock source is 1 kHz LPO clock.
3. ACMP adder cause <1 μA I_{DD} increase typically.
4. The current varies with TSI configuration and capacity of touch electrode. Please refer to [TSI electrical specifications](#).
5. LVD is periodically woken up from stop3 by 5% duty cycle. The period is equal to or less than 2 ms.

5.1.3 EMC performance

Electromagnetic compatibility (EMC) performance is highly dependant on the environment in which the MCU resides. Board design and layout, circuit topology choices, location and characteristics of external components as well as MCU software operation all play a significant role in EMC performance. The system designer should consult Freescale applications notes such as AN2321, AN1050, AN1263, AN2764, and AN1259 for advice and guidance specifically targeted at optimizing EMC performance.

5.1.3.1 EMC radiated emissions operating behaviors

Table 8. Thermal characteristics

Rating	Symbol	Value	Unit
Operating temperature range (packaged)	T_A	T_L to T_H -40 to 125	$^{\circ}\text{C}$
Junction temperature range	T_J	-40 to 135	$^{\circ}\text{C}$
Thermal resistance single-layer board			
64-pin LQFP	θ_{JA}	71	$^{\circ}\text{C/W}$
48-pin LQFP	θ_{JA}	81	$^{\circ}\text{C/W}$
32-pin LQFP	θ_{JA}	86	$^{\circ}\text{C/W}$
Thermal resistance four-layer board			
64-pin LQFP	θ_{JA}	53	$^{\circ}\text{C/W}$
48-pin LQFP	θ_{JA}	57	$^{\circ}\text{C/W}$
32-pin LQFP	θ_{JA}	57	$^{\circ}\text{C/W}$

The average chip-junction temperature (T_J) in $^{\circ}\text{C}$ can be obtained from:

$$T_J = T_A + (P_D \times \theta_{JA})$$

Where:

T_A = Ambient temperature, $^{\circ}\text{C}$

θ_{JA} = Package thermal resistance, junction-to-ambient, $^{\circ}\text{C/W}$

$$P_D = P_{\text{int}} + P_{\text{I/O}}$$

P_{int} = $I_{\text{DD}} \times V_{\text{DD}}$, Watts - chip internal power

$P_{\text{I/O}}$ = Power dissipation on input and output pins - user determined

For most applications, $P_{\text{I/O}} \ll P_{\text{int}}$ and can be neglected. An approximate relationship between P_D and T_J (if $P_{\text{I/O}}$ is neglected) is:

$$P_D = K \div (T_J + 273 \text{ }^{\circ}\text{C})$$

Solving the equations above for K gives:

$$K = P_D \times (T_A + 273 \text{ }^{\circ}\text{C}) + \theta_{JA} \times (P_D)^2$$

where K is a constant pertaining to the particular part. K can be determined by measuring P_D (at equilibrium) for a known T_A . Using this value of K, the values of P_D and T_J can be obtained by solving the above equations iteratively for any value of T_A .

6 Peripheral operating requirements and behaviors

**Table 9. XOSC and ICS specifications (temperature range = -40 to 125 °C ambient)
(continued)**

Num	C	Characteristic	Symbol	Min	Typical ¹	Max	Unit
11	P	Total deviation of DCO output from trimmed frequency ⁵	$\Delta f_{\text{dco_t}}$	—	—	±2.0	%f _{dco}
	C					±1.5	
	C					±1.0	
12	C	FLL acquisition time ^{5, 7}	t _{Acquire}	—	—	2	ms
13	C	Long term jitter of DCO output clock (averaged over 2 ms interval) ⁸	C _{Jitter}	—	0.02	0.2	%f _{dco}

1. Data in Typical column was characterized at 5.0 V, 25 °C or is typical recommended value.
2. When ICS is configured for FEE or FBE mode, input clock source must be divisible using RDIV to within the range of 31.25 kHz to 39.0625 kHz.
3. See crystal or resonator manufacturer's recommendation.
4. Load capacitors (C₁, C₂), feedback resistor (R_F) and series resistor (R_S) are incorporated internally when RANGE = HGO = 0.
5. This parameter is characterized and not tested on each device.
6. Proper PC board layout procedures must be followed to achieve specifications.
7. This specification applies to any time the FLL reference source or reference divider is changed, trim value changed, DMX32 bit is changed, DRS bit is changed, or changing from FLL disabled (FBELP, FBILP) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.
8. Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{Bus}. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the FLL circuitry via V_{DD} and V_{SS} and variation in crystal oscillator frequency increase the C_{Jitter} percentage for a given interval.

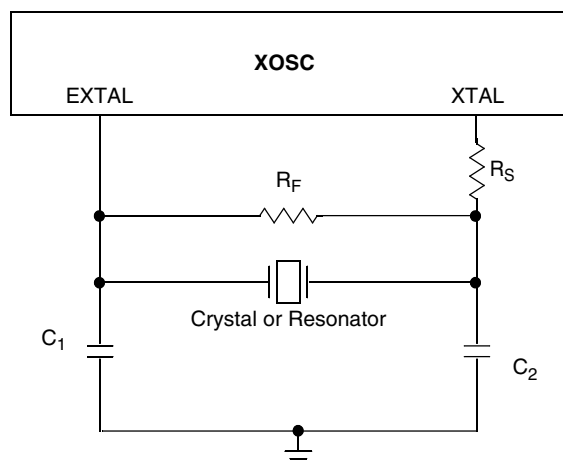


Figure 15. Typical crystal or resonator circuit

6.2 NVM specifications

This section provides details about program/erase times and program/erase endurance for the flash and EEPROM memories.

Table 10. Flash characteristics

C	Characteristic	Symbol	Min ¹	Typical ²	Max ³	Unit ⁴
D	Supply voltage for program/erase -40 °C to 125 °C	V _{prog/erase}	2.7	—	5.5	V
D	Supply voltage for read operation	V _{Read}	2.7	—	5.5	V
D	NVM Bus frequency	f _{NVMBUS}	1	—	25	MHz
D	NVM Operating frequency	f _{NVMOP}	0.8	1	1.05	MHz
D	Erase Verify All Blocks	t _{VFYALL}	—	—	17338	t _{cyc}
D	Erase Verify Flash Block	t _{RD1BLK}	—	—	16913	t _{cyc}
D	Erase Verify EEPROM Block	t _{RD1BLK}	—	—	810	t _{cyc}
D	Erase Verify Flash Section	t _{RD1SEC}	—	—	484	t _{cyc}
D	Erase Verify EEPROM Section	t _{DRD1SEC}	—	—	555	t _{cyc}
D	Read Once	t _{RDONCE}	—	—	450	t _{cyc}
D	Program Flash (2 word)	t _{PGM2}	0.12	0.12	0.29	ms
D	Program Flash (4 word)	t _{PGM4}	0.20	0.21	0.46	ms
D	Program Once	t _{PGMONCE}	0.20	0.21	0.21	ms
D	Program EEPROM (1 Byte)	t _{DPGM1}	0.10	0.10	0.27	ms
D	Program EEPROM (2 Byte)	t _{DPGM2}	0.17	0.18	0.43	ms
D	Program EEPROM (3 Byte)	t _{DPGM3}	0.25	0.26	0.60	ms
D	Program EEPROM (4 Byte)	t _{DPGM4}	0.32	0.33	0.77	ms
D	Erase All Blocks	t _{ERSALL}	96.01	100.78	101.49	ms
D	Erase Flash Block	t _{ERSBLK}	95.98	100.75	101.44	ms
D	Erase Flash Sector	t _{ERSPG}	19.10	20.05	20.08	ms
D	Erase EEPROM Sector	t _{DERSPG}	4.81	5.05	20.57	ms
D	Unsecure Flash	t _{UNSECU}	96.01	100.78	101.48	ms
D	Verify Backdoor Access Key	t _{VFYKEY}	—	—	464	t _{cyc}
D	Set User Margin Level	t _{MLOADU}	—	—	407	t _{cyc}
C	FLASH Program/erase endurance T _L to T _H = -40 °C to 125 °C	n _{FLPE}	10 k	100 k	—	Cycles
C	EEPROM Program/erase endurance T _L to T _H = -40 °C to 125 °C	n _{FLPE}	50 k	500 k	—	Cycles
C	Data retention at an average junction temperature of T _{Javg} = 85°C after up to 10,000 program/erase cycles	t _{D_ret}	15	100	—	years

1. Minimum times are based on maximum f_{NVMOP} and maximum f_{NVMBUS}
2. Typical times are based on typical f_{NVMOP} and maximum f_{NVMBUS}
3. Maximum times are based on typical f_{NVMOP} and typical f_{NVMBUS} plus aging
4. t_{cyc} = 1 / f_{NVMBUS}

Program and erase operations do not require any special power sources other than the normal V_{DD} supply. For more detailed information about program/erase operations, see the Memory section.

6.3 Analog

6.3.1 ADC characteristics

Table 11. 5 V 12-bit ADC operating conditions

Characteristic	Conditions	Symb	Min	Typ ¹	Max	Unit	Comment
Supply voltage	Absolute	V_{DDA}	2.7	—	5.5	V	—
	Delta to V_{DD} ($V_{DD}-V_{DDAD}$)	ΔV_{DDA}	-100	0	+100	mV	
Ground voltage	Delta to V_{SS} ($V_{SS}-V_{SSA}$) ²	ΔV_{SSA}	-100	0	+100	mV	
Input voltage		V_{ADIN}	V_{REFL}	—	V_{REFH}	V	
Input capacitance		C_{ADIN}	—	4.5	5.5	pF	
Input resistance		R_{ADIN}	—	3	5	k Ω	—
Analog source resistance	12-bit mode	R_{AS}	—	—	2	k Ω	External to MCU
	• $f_{ADCK} > 4$ MHz		—	—	5		
	• $f_{ADCK} < 4$ MHz		—	—	5		
	10-bit mode		—	—	5		
	• $f_{ADCK} > 4$ MHz		—	—	10		
	• $f_{ADCK} < 4$ MHz		—	—	10		
	8-bit mode		—	—	10		
ADC conversion clock frequency	High speed (ADLPC=0)	f_{ADCK}	0.4	—	8.0	MHz	—
	Low power (ADLPC=1)		0.4	—	4.0		

1. Typical values assume $V_{DDA} = 5.0$ V, Temp = 25°C, $f_{ADCK}=1.0$ MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
2. DC potential difference.

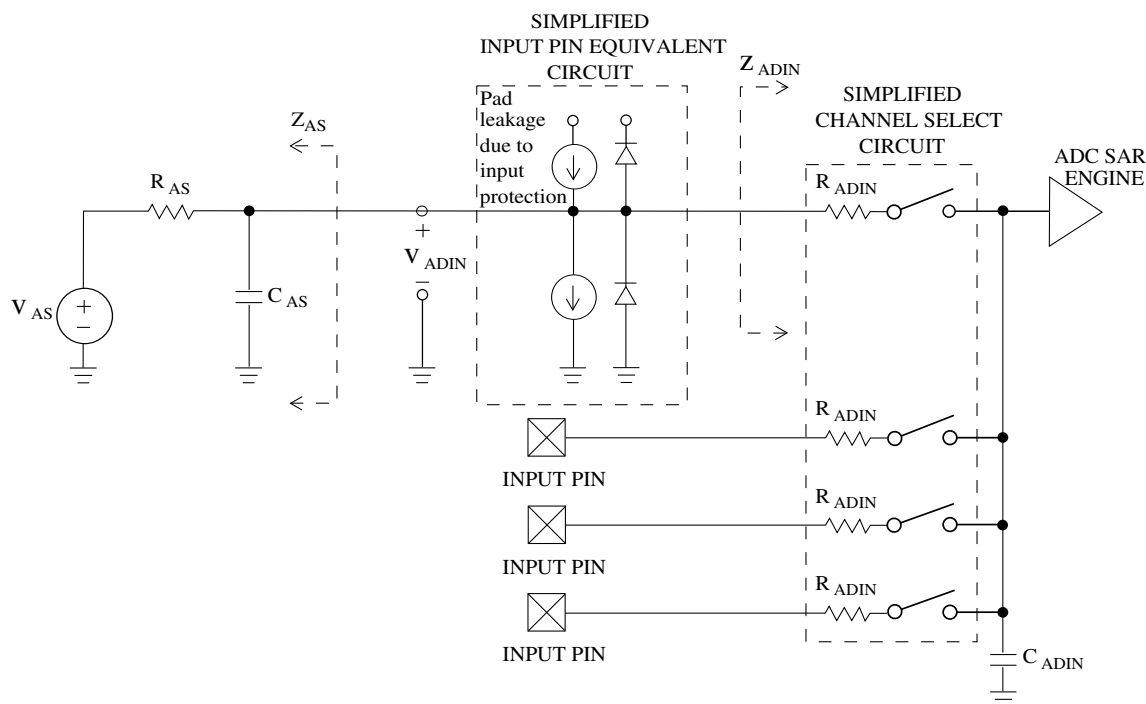


Figure 16. ADC input impedance equivalency diagram

Table 12. 12-bit ADC Characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$)

Characteristic	Conditions	C	Symb	Min	Typ ¹	Max	Unit
Supply current ADLPC = 1 ADLSMP = 1 ADCO = 1		T	I_{DDA}	—	133	—	μA
Supply current ADLPC = 1 ADLSMP = 0 ADCO = 1		T	I_{DDA}	—	218	—	μA
Supply current ADLPC = 0 ADLSMP = 1 ADCO = 1		T	I_{DDA}	—	327	—	μA
Supply current ADLPC = 0 ADLSMP = 0 ADCO = 1		T	I_{DDAD}	—	582	990	μA
Supply current Stop, reset, module off		T	I_{DDA}	—	0.011	1	μA

Table continues on the next page...

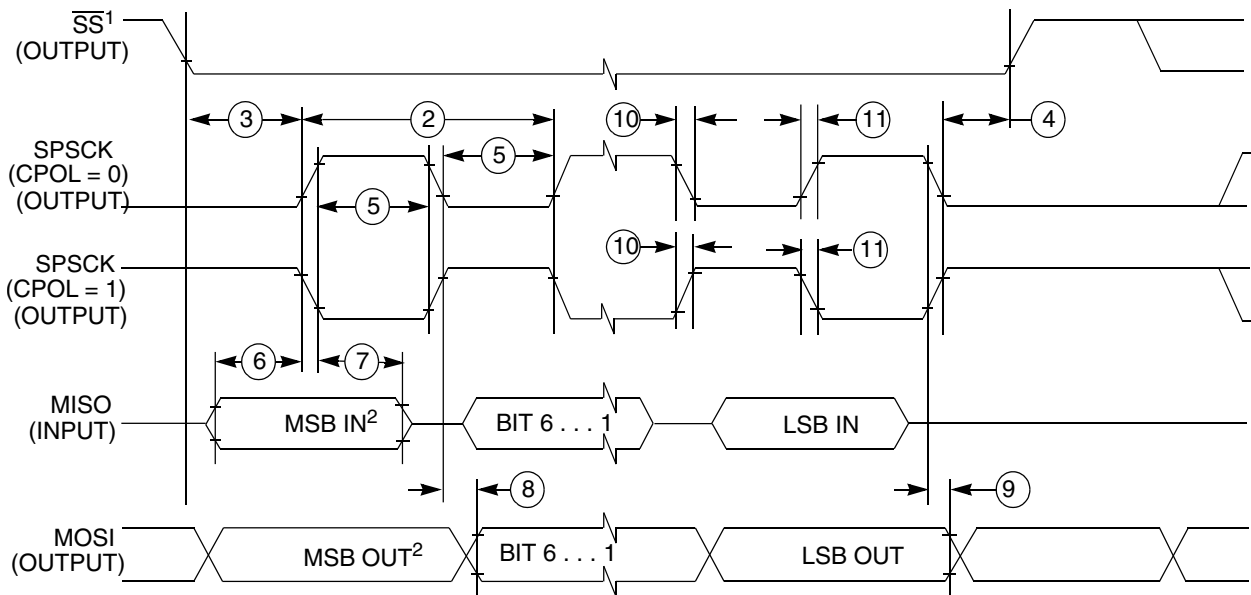
Table 12. 12-bit ADC Characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

Characteristic	Conditions	C	Symb	Min	Typ ¹	Max	Unit
ADC asynchronous clock source	High speed (ADLPC = 0)	P	f_{ADACK}	2	3.3	5	MHz
	Low power (ADLPC = 1)			1.25	2	3.3	
Conversion time (including sample time)	Short sample (ADLSMP = 0)	T	t_{ADC}	—	20	—	ADCK cycles
	Long sample (ADLSMP = 1)			—	40	—	
Sample time	Short sample (ADLSMP = 0)	T	t_{ADS}	—	3.5	—	ADCK cycles
	Long sample (ADLSMP = 1)			—	23.5	—	
Total unadjusted Error ^{2, 2}	12-bit mode	T	E_{TUE}	—	±5.0	—	LSB ^{3, 3}
	10-bit mode	P		—	±1.5	±2.0	
	8-bit mode	P		—	±0.7	±1.0	
Differential Non-Linearity	12-bit mode	T	DNL	—	±1.0	—	LSB ³
	10-bit mode ^{4, 4}	P		—	±0.25	±0.5	
	8-bit mode ⁴	P		—	±0.15	±0.25	
Integral Non-Linearity	12-bit mode	T	INL	—	±1.0	—	LSB ³
	10-bit mode	T		—	±0.3	±0.5	
	8-bit mode	T		—	±0.15	±0.25	
Zero-scale error ^{5, 5}	12-bit mode	C	E_{ZS}	—	±2.0	—	LSB ³
	10-bit mode	P		—	±0.25	±1.0	
	8-bit mode	P		—	±0.65	±1.0	
Full-scale error ⁶	12-bit mode	T	E_{FS}	—	±2.5	—	LSB ³
	10-bit mode	T		—	±0.5	±1.0	
	8-bit mode	T		—	±0.5	±1.0	
Quantization error	≤12 bit modes	D	E_Q	—	—	±0.5	LSB ³
Input leakage error ⁷	all modes	D	E_{IL}	$I_{in} * R_{AS}$			mV
Temp sensor slope	-40°C– 25°C	D	m	—	3.266	—	mV/°C
	25°C– 125°C			—	3.638	—	
Temp sensor voltage	25°C	D	V_{TEMP25}	—	1.396	—	V

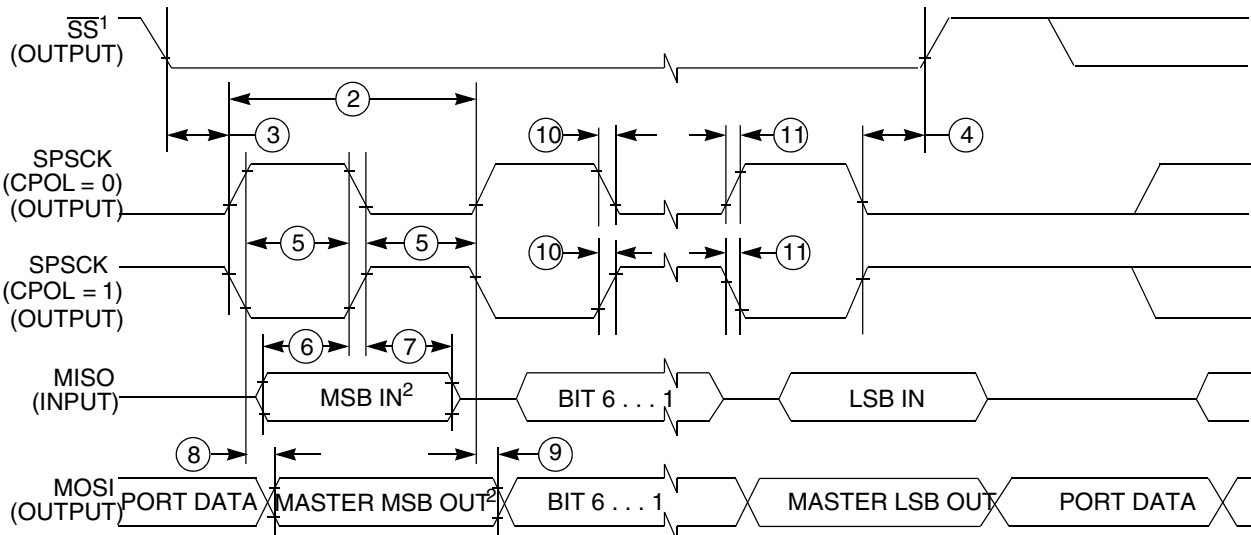
1. Typical values assume $V_{DDA} = 5.0$ V, Temp = 25°C, $f_{ADCK}=1.0$ MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
2. Includes quantization.
3. $1 \text{ LSB} = (V_{REFH} - V_{REFL})/2^N$
4. Monotonicity and no-missing-codes guaranteed in 10-bit and 8-bit modes
5. $V_{ADIN} = V_{SSA}$
6. $V_{ADIN} = V_{DDA}$
7. I_{in} = leakage current (refer to DC characteristics)

Table 14. SPI master mode timing (continued)

Nu m.	Symbol	Description	Min.	Max.	Unit	Comment
10	t_{RI}	Rise time input	—	$t_{Bus} - 25$	ns	—
	t_{FI}	Fall time input				
11	t_{RO}	Rise time output	—	25	ns	—
	t_{FO}	Fall time output				



1. If configured as an output.
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 17. SPI master mode timing (CPHA=0)


1. If configured as output
2. LSBF = 0. For LSBF = 1, bit order is LSB, bit 1, ..., bit 6, MSB.

Figure 18. SPI master mode timing (CPHA=1)

To find a package drawing, go to freescale.com and perform a keyword search for the drawing's document number:

If you want the drawing for this package	Then use this document number
32-pin LQFP	98ASH70029A
48-pin LQFP	98ASH00962A
64-pin LQFP	98ASS23234W

8 Pinout

8.1 Signal multiplexing and pin assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

Table 17. Pin availability by package pin-count

Pin Number			Lowest Priority <-- --> Highest				
64-LQFP	48-LQFP	32-LQFP	Port Pin	Alt 1	Alt 2	Alt 3	Alt 4
1	1	1	PTD1 ^{1, 1}	KBI1P1	FTM2CH3	MOSI1	—
2	2	2	PTD0 ¹	KBI1P0	FTM2CH2	SPSCK1	—
3	—	—	PTH7	—	—	—	—
4	—	—	PTH6	—	—	—	—
5	3	—	PTE7	—	TCLK2	—	—
6	4	—	PTH2	—	BUSOUT	—	—
7	5	3	—	—	—	—	V _{DD}
8	6	4	—	—	—	V _{DDA}	V _{REFH}
9	7	5	—	—	—	V _{SSA}	V _{REFL}
10	8	6	—	—	—	—	V _{SS}
11	9	7	PTB7	—	SCL	—	EXTAL
12	10	8	PTB6	—	SDA	—	XTAL
13	11	—	—	—	—	—	V _{SS}
14	—	—	PTH1 ¹	—	FTM2CH1	—	—
15	—	—	PTH0 ¹	—	FTM2CH0	—	—
16	12	—	PTE6	—	—	—	—
17	13	—	PTE5	—	—	—	—
18	14	9	PTB5 ¹	FTM2CH5	SS0	—	—
19	15	10	PTB4 ¹	FTM2CH4	MISO0	—	—

Table continues on the next page...

Table 17. Pin availability by package pin-count (continued)

Pin Number			Lowest Priority <-- --> Highest				
64-LQFP	48-LQFP	32-LQFP	Port Pin	Alt 1	Alt 2	Alt 3	Alt 4
20	16	11	PTC3	FTM2CH3	—	ADP11	—
21	17	12	PTC2	FTM2CH2	—	ADP10	—
22	18	—	PTD7	KBI1P7	TXD2	—	—
23	19	—	PTD6	KBI1P6	RXD2	—	—
24	20	—	PTD5	KBI1P5	—	—	—
25	21	13	PTC1	—	FTM2CH1	ADP9	TSI7
26	22	14	PTC0	—	FTM2CH0	ADP8	TSI6
27	—	—	PTF7	—	—	ADP15	—
28	—	—	PTF6	—	—	ADP14	—
29	—	—	PTF5	—	—	ADP13	—
30	—	—	PTF4	—	—	ADP12	—
31	23	15	PTB3	KBI0P7	MOSI0	ADP7	TSI5
32	24	16	PTB2	KBI0P6	SPSCK0	ADP6	TSI4
33	25	17	PTB1	KBI0P5	TXD0	ADP5	TSI3
34	26	18	PTB0	KBI0P4	RXD0	ADP4	TSI2
35	—	—	PTF3	—	—	—	TSI15
36	—	—	PTF2	—	—	—	TSI14
37	27	19	PTA7	FTM2FAULT2	—	ADP3	TSI1
38	28	20	PTA6	FTM2FAULT1	—	ADP2	TSI0
39	29	—	PTE4	—	—	—	—
40	30	—	—	—	—	—	V _{SS}
41	31	—	—	—	—	—	V _{DD}
42	—	—	PTF1	—	—	—	TSI13
43	—	—	PTF0	—	—	—	TSI12
44	32	—	PTD4	KBI1P4	—	—	—
45	33	21	PTD3	KBI1P3	SS1	—	TSI11
46	34	22	PTD2	KBI1P2	MISO1	—	TSI10
47	35	23	PTA3 ^{2, 2}	KBI0P3	TXD0	SCL	—
48	36	24	PTA2 ²	KBI0P2	RXD0	SDA	—
49	37	25	PTA1	KBI0P1	FTM0CH1	ACMP1	ADP1
50	38	26	PTA0	KBI0P0	FTM0CH0	ACMP0	ADP0
51	39	27	PTC7	—	TxD1	—	TSI9
52	40	28	PTC6	—	RxD1	—	TSI8
53	41	—	PTE3	—	SS0	—	—
54	42	—	PTE2	—	MISO0	—	—
55	—	—	PTG3	—	—	—	—
56	—	—	PTG2	—	—	—	—
57	—	—	PTG1	—	—	—	—

Table continues on the next page...

Table 17. Pin availability by package pin-count (continued)

Pin Number			Lowest Priority <-- --> Highest				
64-LQFP	48-LQFP	32-LQFP	Port Pin	Alt 1	Alt 2	Alt 3	Alt 4
58	—	—	PTG0	—	—	—	—
59	43	—	PTE1 ¹	—	MOSI0	—	—
60	44	—	PTE0 ¹	—	SPSCK0	TCLK1	—
61	45	29	PTC5	—	FTM1CH1	—	—
62	46	30	PTC4	—	FTM1CH0	RTCO	—
63	47	31	—	—	—	—	RESET
64	48	32	—	—	—	BKGD	MS

1. This is a high current drive pin when operated as output.
2. This is a true open-drain pin when operated as output.

Note

When an alternative function is first enabled, it is possible to get a spurious edge to the module. User software must clear any associated flags before interrupts are enabled. The table above illustrates the priority if multiple modules are enabled. The highest priority module will have control over the pin. Selecting a higher priority pin function with a lower priority function already enabled can cause spurious edges to the lower priority module. Disable all modules that share a pin before enabling another module.

8.2 Device pin assignment

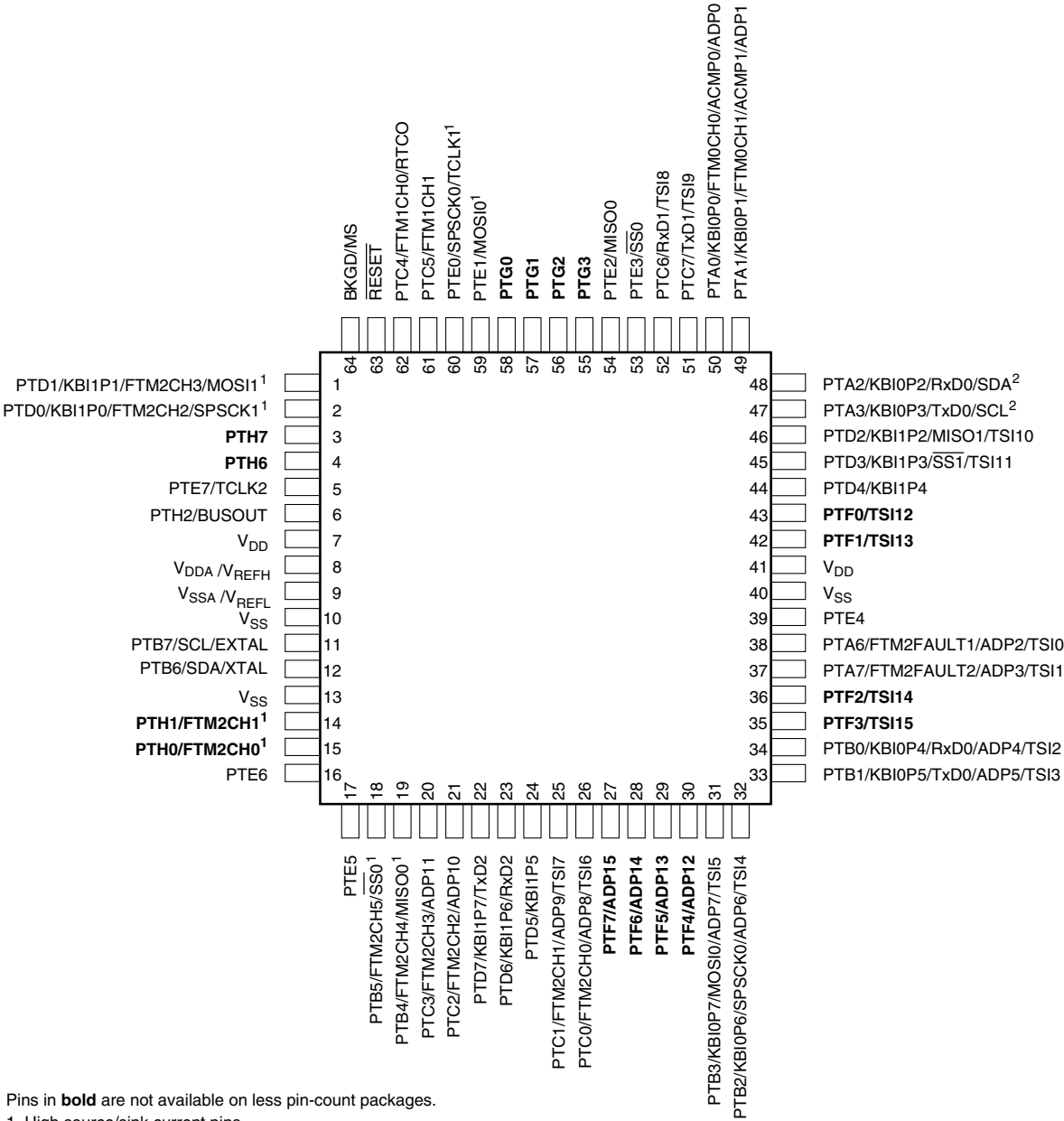


Figure 21. S9S08RN60 64-pin LQFP package

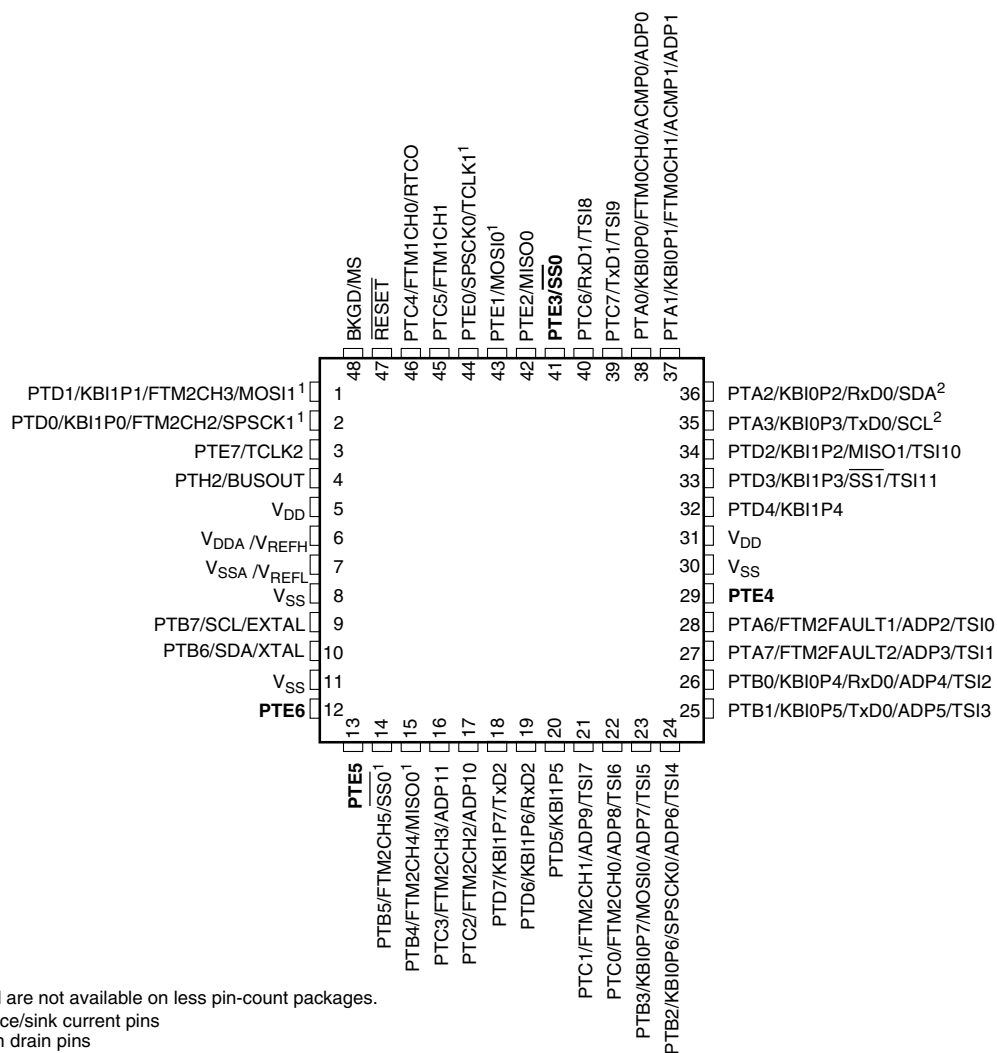


Figure 22. S9S08RN60 48-pin LQFP package